### **DEPFET TB 2010**



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# 5<sup>th</sup> DEPFET workshop – IFIC Valencia, Sep 30<sup>th</sup> 2010 -

### **Marcel Vos, IFIC Valencia**





EPFET workshop, Sep 30<sup>th</sup>, 2010

#### SPS Operation

#### Period 6 2010 Oct 21 to Nov 22

Schedule Issue date: 15-April-2010 Ver

0 Version 2.0

(colour code: purple (dark) = scheduling meeting , light green (light) = weekend or holiday)



TB2010, our beam period: 15-21 November Last slot of the season, after SiLC (parasitic operation possible) EUDET telescope requested TB period clashes with B2GM Some people have already indicated they are not available TB period clashes with PXD6 testing Assume some people are needed elsewhere

Required: (EU) DAQ: Sergey & Julia (Bonn), Jochen (Hei) + ? DUT operation: Jochen (Hei) Characterization (at MPI): Jelena, Christian K. (MPI) + ? Analysis team: Benjamin S. (Gö) + Guillermo (Val) + ? Mechanics: Carlos (Val)

Requested EU funding (EUDET) for travel and stay. Have to give names in two weeks

## **TB2010: DUT**

# S3B module based on PXD5 with 4 um gate length DCDB-based PXD5 DUT (on hybrid 4.1)

- (Nearly) full-speed read out row rate/nominal ~ 3, compared to several orders of magnitude with previous system)
- Relevant pedestals, common mode but custom power supplies, cables, etc.
- 3) Possibly PXD6 module
  - mm<sup>2</sup> device, ILC design affected by yield problem, but feasible
  - First thin DEPFET



#### **DCDB read-out scheme** $\rightarrow$ feed-back from experts:

full speed out of the question after Jochen's presentation

#### Characterization of device $\rightarrow$ assign responsible groups:

Matrix optimization (gate, source voltage scan with laser, calibration with source) DCDB calibration (needed to get  $g_{a}$ )



#### Focus of the program

A "read-out" program varying DCDB parameters, if (1) A "thin sensor" program with angle scans, if (2) Be ready for either

# Telescope: use either EUDET (3-5 $\mu$ m pointing precision) or S3B telescope used in 2009 (1 $\mu$ m pointing precision)



Choice entirely driven by desire to minimize our requirements on limited DEPFET resources (manpower, mostly) Will have serious difficulties to characterize the resolution of PXD5 DEPFET devices A TB always comes with the risk of encountering a problem that cannot be solved in time. With EUDET, it's not even in our hands to solve it.

## **TB2010:** analysis

The analysis team present at the TB is responsible for validating the data (quasionline monitoring), for documenting what happened and for preprocessing the data. Will be reinforced by people back from B2GM: expect serious effort from at least two experienced teams (Pr, Gö, Bonn) + some students (Val, ...)

My proposal: produce a few basic plots (S/N,  $g_q$ , resolution vs. angle, bias voltage) rapidly (~January/February) that can go into a brief publication by the DEPFET collaboration "Performance of (thin) DEPFET active pixel sensors (with fast read-out)". This is not a TB paper, but an announcement of a major step made by the collaboration as a whole, with some TB results

This does not exclude the possibility that a TB paper with a more involved analysis can be written at a later stage.



Beam requests typically due by Christmas Remember: SPS may not be active in 2012. Want to demonstrate performance of aBelle-II half-ladder with nominal read-out speed. More than one period is a too large effort.

Proposal: one-week period early in the season... June/July.



## **TB2010**

# Options we will have in case of ...

PXD6 DCDB	On time	Late
YES	PXD6 ILC type matrix 24x24µm <sup>2</sup> or 20x20µm <sup>2</sup> & DCDB/DCDRO test system for ILC type matrix	PXD5 ILC type matrix 24x24µm <sup>2</sup> or 20x20µm <sup>2</sup> & DCDB/DCDRO test system for ILC type matrix
NO	PXD6 ILC type matrix 24x24µm <sup>2</sup> or 20x20µm <sup>2</sup> & S3B test system for ILC type matrix - modified -	PXD5 ILC tor trix 24x24µm <sup>2</sup> 009 trix TB2 or system for LC type matrix

<u>year</u>	Tentative title of TB paper	
2008/2009	TB of the PXD5 production of DEPFET activ Micron resolution device, Digitizer validation	e pixel sensors
Nov 2010	TB of (thin) DEPFET a.p.s. (with full speed re Study realistic pedestals/common-mode	ead-out)
July 2011?	TB of Belle-II PXD prototypes Show this meets the requirements	
DEPFET workshop. Sep	30 <sup>th</sup> . 2010 8 Marce	el.Vos@ific.uv.es